

Form PTO-1449 (modified)	Atty. Docket No. 2000.088500/TT4616	Serial No. 10/700,175
List of Patents and Publications for Applicant's INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	Applicant Elfido Coss, Jr., Patrick M. Cowan, Richard J. Markle and Tom Tse	
	Filing Date: November 3, 2003	Group: 2812 2881
U.S. Patent Documents See Page 1	Foreign Patent Documents See Page 1	Other Art See Page 1

U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
115	A2	6,055,460	4/25/00	Shopbell	700	121	
115	A3	2002/0055801 A1	5/09/02	Reiss <i>et al.</i>	700	111	
115	A4	2003/0042427 A1	3/06/03	Sullivan <i>et al.</i>	250	397	
	A5						
	A6						

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						
	B2						
	B3						

Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
115	C1	PCT Search Report from PCT/US2004/017617, dated 12/02/04
115	C2	Rendon <i>et al.</i> , "Ion Implant Data Log Analysis for Process Control and Fault Detection," <i>IEEE</i> , pp. 331-334, 2002
	C3	

EXAMINER:

Michael J. Wells

DATE CONSIDERED:

May 4, 2005

EXAMINER: INITIAL IF REFERENCE CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED. INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.



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INFORMATION DISCLOSURE STATEMENT

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Applicant

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and Tom Tse

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Foreign Patent Documents

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Other Art

See Page 1

U.S. Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Name	Class	Sub Class	Filing Date of App.
11B	A1	6,465,263 B1	10/15/02	Coss, Jr. <i>et al.</i>	438	14	
	A2						
	A3						
	A4						
	A5						

Foreign Patent Documents

Exam. Init.	Ref. Des.	Document Number	Date	Country	Class	Sub Class	Translation Yes/No
	B1						
	B2						
	B3						

Other Art (Including Author, Title, Date Pertinent Pages, Etc.)

Exam. Init.	Ref. Des.	Citation
	C1	
	C2	
	C3	

EXAMINER:

Nichita Wells

DATE CONSIDERED:

May 7, 2005

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